PH3075L

N-channel TrenchMOS logic level FET

Rev. 02 — 23 February 2009

Product data sheet

1. Product profile

1.1 General description

Logic level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology. This product is designed and qualified for use in computing, communications, consumer and industrial applications only.

1.2 Features and benefits

- Low conduction losses due to low on-state resistance
- Suitable for logic level gate drive sources
- Suitable for thermally demanding environments due to 175 °C rating

1.3 Applications

- DC motor control
- DC-to-DC convertors

General purpose power switching

1.4 Quick reference data

Table 1. Quick reference

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V_{DS}	drain-source voltage	$T_j \ge 25 \text{ °C}; T_j \le 175 \text{ °C}$	-	-	75	V
I_D	drain current	T _{mb} = 25 °C; V _{GS} = 5 V; see <u>Figure 1</u> ; see <u>Figure 3</u>	-	-	30	Α
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>	-	-	75	W
Dynamic	characteristics					
Q_{GD}	gate-drain charge	$V_{GS} = 5 \text{ V; } I_D = 25 \text{ A;}$ $V_{DS} = 60 \text{ V; } T_j = 25 \text{ °C;}$ see Figure 11	-	9	-	nC
Static ch	naracteristics					
R _{DSon}	drain-source on-state resistance	$V_{GS} = 10 \text{ V}; I_D = 15 \text{ A};$ $T_j = 25 \text{ °C}; \text{ see } \frac{\text{Figure 9}}{\text{see } \frac{\text{Figure 10}}{\text{otherwise}}}$	-	23	28	mΩ



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2. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	S	source		
2	S	source	mb	D
3	S	source		$G \longrightarrow \overline{A}$
4	G	gate	q	<u> </u>
mb	D	mounting base; connected to drain	1 2 3 4	mbb076 S
			SOT669 (LFPAK)	

3. Ordering information

Table 3. Ordering information

Type number	Package		
	Name	Description	Version
PH3075L	LFPAK	plastic single-ended surface-mounted package (LFPAK); 4 leads	SOT669

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4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

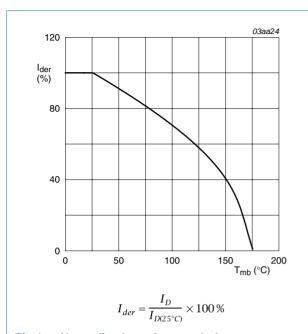
Symbol	Parameter	Conditions		Min	Max	Unit
V_{DS}	drain-source voltage	$T_j \ge 25 \text{ °C}; T_j \le 175 \text{ °C}$		-	75	V
V_{DGR}	drain-gate voltage	$T_j \ge 25 \text{ °C}; T_j \le 175 \text{ °C}; R_{GS} = 20 \text{ k}\Omega$		-	75	V
V_{GS}	gate-source voltage			-15	15	V
I_D	drain current	V _{GS} = 5 V; T _{mb} = 100 °C; see <u>Figure 1</u>		-	21	Α
		$V_{GS} = 5 \text{ V}; T_{mb} = 25 \text{ °C}; \text{ see } \underline{\text{Figure 1}}; \text{ see } \underline{\text{Figure 3}}$		-	30	Α
I_{DM}	peak drain current	$t_p \le 10 \ \mu s$; pulsed; $T_{mb} = 25 \ ^{\circ}C$; see <u>Figure 3</u>		-	120	Α
P_{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>		-	75	W
T _{stg}	storage temperature			-55	175	°C
Tj	junction temperature			-55	175	°C
Source-dr	ain diode					
Is	source current	$T_{mb} = 25 ^{\circ}C$		-	30	Α
I _{SM}	peak source current	$t_p \le 10 \ \mu s$; pulsed; $T_{mb} = 25 \ ^{\circ}C$		-	120	Α
Avalanche	ruggedness					
E _{DS(AL)R}	repetitive drain-source avalanche energy	V_{GS} = 10 V; I_D = 3 A; $V_{sup} \le 75$ V; unclamped; R_{GS} = 50 Ω ;	[1][2]	-	0.89	mJ
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	V_{GS} = 10 V; $T_{j(init)}$ = 25 °C; I_D = 30 A; V_{sup} ≤ 75 V; unclamped; R_{GS} = 50 Ω		-	89	mJ

^[1] Duty cycle is limited by the maximum junction temperature.

^[2] Repetitive avalanche failure is not determined simply by thermal effects. Repetitive avalanche transients should only be applied for short bursts, not every switching cycle.

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Normalized continuous drain current as a function of mounting base temperature

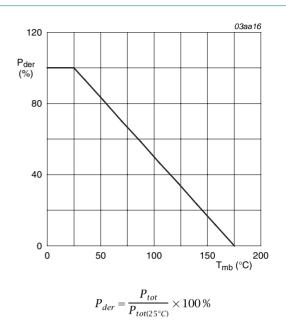
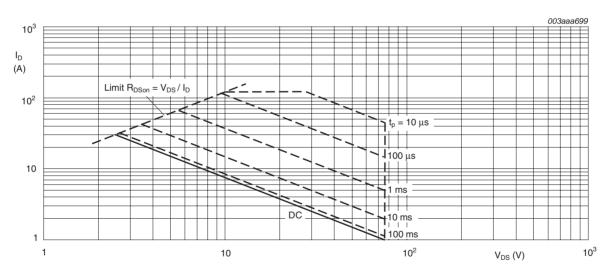


Fig 2. Normalized total power dissipation as a function of mounting base temperature

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 $T_{mb} = 25$ °C; I_{DM} is single pulse

Safe operating area; continuous and peak drain currents as a function of drain-source voltage Fig 3.

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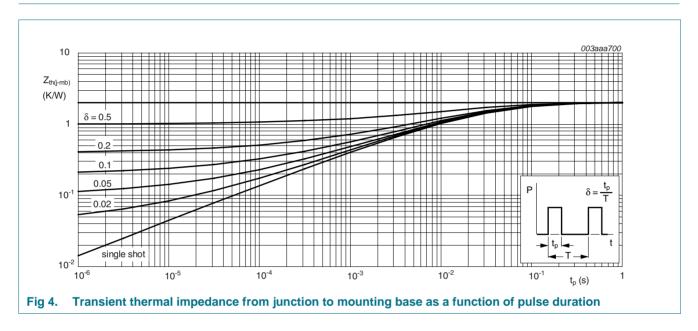
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Thermal characteristics 5.

Thermal characteristics Table 5.

Product data sheet

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{th(j-mb)}$	thermal resistance from junction to mounting base	see Figure 4	-	-	2	K/W



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6. Characteristics

Table 6. Characteristics

Table 6.	Characteristics					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	racteristics					
$V_{(BR)DSS}$	drain-source	$I_D = 250 \ \mu A; \ V_{GS} = 0 \ V; \ T_j = -55 \ ^{\circ}C$	70	-	-	V
	breakdown voltage	$I_D = 250 \mu A; V_{GS} = 0 V; T_j = 25 °C$	75	-	-	V
$V_{GS(th)}$	gate-source threshold voltage	$I_D = 1 \text{ mA}$; $V_{DS} = V_{GS}$; $T_j = -55 \text{ °C}$; see <u>Figure 8</u>	-	-	2.3	V
		$I_D = 1$ mA; $V_{DS} = V_{GS}$; $T_j = 25$ °C; see <u>Figure 7</u> ; see <u>Figure 8</u>	1	1.5	2	V
		$I_D = 1$ mA; $V_{DS} = V_{GS}$; $T_j = 175$ °C; see <u>Figure 7</u> ; see <u>Figure 8</u>	0.5	-	-	V
I _{DSS}	drain leakage current	$V_{DS} = 75 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	-	1	μΑ
		$V_{DS} = 75 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 175 \text{ °C}$	-	-	500	μΑ
I _{GSS}	gate leakage current	$V_{GS} = 15 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	2	100	nA
		$V_{GS} = -15 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	2	100	nA
R _{DSon} drain-source on-stresistance	drain-source on-state resistance	$V_{GS} = 5 \text{ V}; I_D = 15 \text{ A}; T_j = 175 °C;$ see <u>Figure 9</u> ; see <u>Figure 10</u>	-	-	72	mΩ
		$V_{GS} = 4.5 \text{ V}; I_D = 15 \text{ A}; T_j = 25 ^{\circ}\text{C};$ see Figure 9; see Figure 10	-	-	34	mΩ
		$V_{GS} = 10 \text{ V}; I_D = 15 \text{ A}; T_j = 25 ^{\circ}\text{C};$ see Figure 9; see Figure 10	-	23	28	mΩ
		$V_{GS} = 5 \text{ V}; I_D = 15 \text{ A}; T_j = 25 ^{\circ}\text{C};$ see Figure 9; see Figure 10	-	25	30	mΩ
Dynamic	characteristics					
Q _{G(tot)}	total gate charge	$I_D = 25 \text{ A}; V_{DS} = 60 \text{ V}; V_{GS} = 5 \text{ V};$	-	19	-	nC
Q _{GS}	gate-source charge	T _j = 25 °C; see <u>Figure 11</u>	-	5	-	nC
Q_{GD}	gate-drain charge		-	9	-	nC
C _{iss}	input capacitance	$V_{DS} = 25 \text{ V}; V_{GS} = 0 \text{ V}; f = 1 \text{ MHz};$	-	1550	2070	pF
C _{oss}	output capacitance	T _j = 25 °C; see <u>Figure 12</u>	-	150	179	pF
C _{rss}	reverse transfer capacitance		-	60	80	pF
d(on)	turn-on delay time	$V_{DS} = 30 \text{ V}; R_L = 1.2 \Omega; V_{GS} = 5 \text{ V};$	-	16	-	ns
t _r	rise time	$R_{G(ext)} = 10 \Omega; T_j = 25 °C$	-	106	-	ns
d(off)	turn-off delay time		-	51	-	ns
t _f	fall time		-	83	-	ns
Source-d	rain diode					
V_{SD}	source-drain voltage	$I_S = 15 \text{ A}$; $V_{GS} = 0 \text{ V}$; $T_j = 25 \text{ °C}$; see Figure 13	-	0.85	1.2	V
t _{rr}	reverse recovery time	$I_S = 20 \text{ A}; dI_S/dt = -100 \text{ A/µs}; V_{GS} = -10 \text{ V};$	-	100	-	ns
Q _r	recovered charge	$V_{DS} = 30 \text{ V}; T_j = 25 \text{ °C}$	-	115	-	nC

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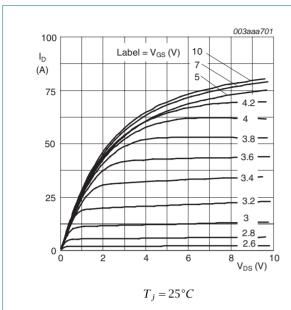
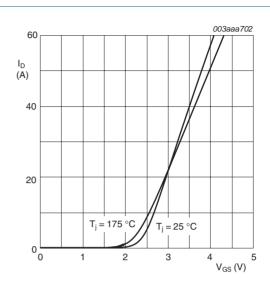


Fig 5. Output characteristics: drain current as a function of drain-source voltage; typical values



 $T_j = 25$ °C and 175°C; $V_{DS} > I_D \times R_{DSon}$

Fig 6. Transfer characteristics: drain current as a function of gate-source voltage; typical values

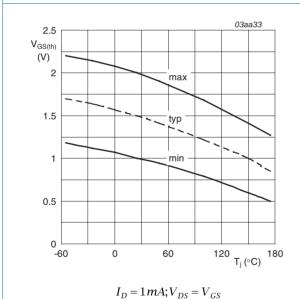
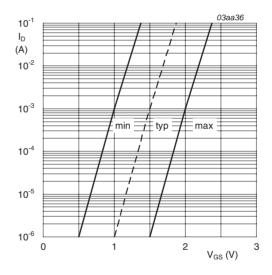


Fig 7. Gate-source threshold voltage as a function of junction temperature



 $T_j = 25 \,^{\circ}C; V_{DS} = V_{GS}$

Fig 8. Sub-threshold drain current as a function of gate-source voltage

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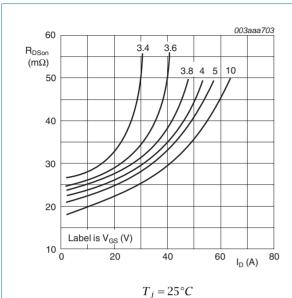


Fig 9. Drain-source on-state resistance as a function of drain current; typical values

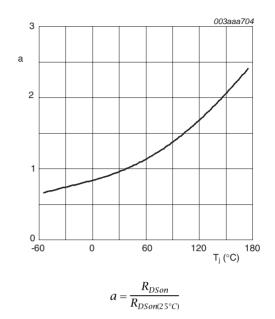
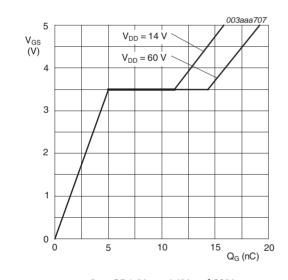
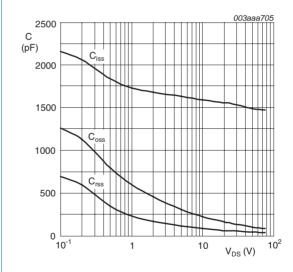


Fig 10. Normalized drain-source on-state resistance factor as a function of junction temperature



 $I_D = 25A; V_{Ds} = 14V \text{ and } 60V$

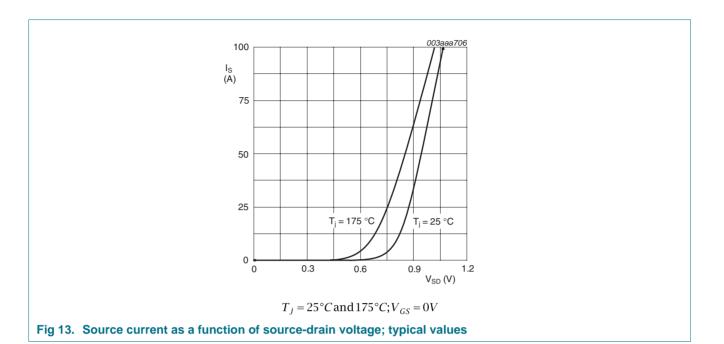
Fig 11. Gate-source voltage as a function of gate charge; typical values



 $V_{GS} = 0V; f = 1MHz$

Fig 12. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values

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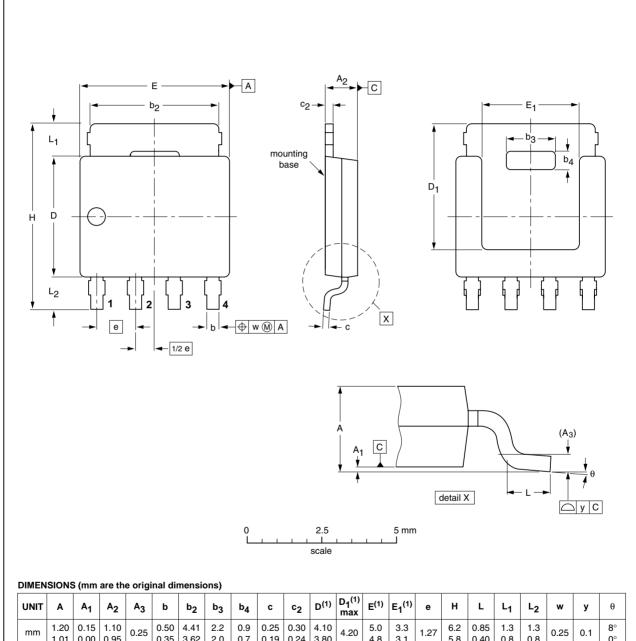


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Package outline

Plastic single-ended surface-mounted package (LFPAK); 4 leads

SOT669



UNIT	Α	A ₁	A ₂	A ₃	b	b ₂	b ₃	b ₄	С	c ₂	D ⁽¹⁾	D ₁ ⁽¹⁾ max	E ⁽¹⁾	E ₁ ⁽¹⁾	е	Н	L	L ₁	L ₂	w	у	θ
mm	1.20 1.01	0.15 0.00	1.10 0.95	0.25	0.50 0.35	4.41 3.62	2.2 2.0	0.9 0.7	0.25 0.19	l .	4.10 3.80	4.20	5.0 4.8	3.3 3.1	1.27	6.2 5.8	0.85 0.40	1.3 0.8	1.3 0.8	0.25	0.1	8° 0°

1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.

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	MO-235			04-10-13 06-03-16	
_	IEC				

Fig 14. Package outline SOT669 (LFPAK)

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8. Revision history

Table 7. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes				
PH3075L_2	20090223	Product data sheet	-	PH3075L_1				
 Modifications: The format of this data sheet has been redesigned to comply with the new identity guidelines of NXP Semiconductors. 								
	 Legal texts 	have been adapted to the	new company name wh	ere appropriate.				
PH3075L_1 (9397 750 14603)	20050225	Product data sheet	-	-				

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9. Legal information

9.1 Data sheet status

Document status [1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
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